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Computer Vision and Sensing Technologies for Industrial Quality Inspection

Message from the Guest Editors

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cases of artificial intelligence techniques and showcases the need to optimize algorithms, inference frameworks, and hardware accelerators to obtain good performance in quality inspection. It mainly focuses on computer vision and sensing technologies for industrial quality inspection, including, but not limited to, imaging techniques, image processing methods, vision systems, and optimization. Industrial inspection papers are also welcome, such as quality inspection with machine learning and data-driven methods. Both review articles and original research papers are sought in this special issue.

This special issue calls for research papers through use

Deadline for manuscript submissions:

closed (25 July 2024)













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